



DELIVERABLE
IST-2001-12529
PROFIT

Deliverable D8.1.2.
PR-INPG-0201-68-benoit
February 2002

Dissemination report M24

Project Number	:	IST – 2001 -12529
Project Title	:	PROFIT
Deliverable Type	:	Report

Deliverable Number	:	D8.1.2.
Internal Project Number	:	PR-INPG-0201-68-benoit
Contractual Delivery Date	:	31 December 2001
Actual Date of Delivery	:	February 2002
Title of Deliverable	:	Dissemination Report M24
Contributing workpackage	:	8
Nature of Deliverable	:	Report
Author(s)	:	TIMA

Abstract

This report is on the dissemination actions.

Keyword list

Dissemination, Workshop.

1. Objectives of the WP

This WP is devoted to various tasks enabling the dissemination and standardisation of appropriate project results. The three objectives are:

- The organisation of yearly open workshops facilitating peer review and early dissemination.
- Various papers to be submitted to workshops and other relevant international conferences.
- Standardisation of transient thermal characterisation methods.

2. Organisation of open workshops

The full programme of THERMINIC 2001 has been set up, including a half-day on Dynamic Measurements organized by PROFIT (*TIMA, TUB, MicRed, PhR*)

The Workshop has been held in Paris, 24-27 September 2001. The Programme Committee of the Workshop was set up as follows.

Workshop Committee:

General Chair	:	B. Courtois, TIMA, Grenoble, France
Vice General-Chair	:	M. Rencz, BUTE, Hungary
Programme Chairs	:	C. Lasance, Philips, The Netherlands
	:	V. Székely, BUTE, Hungary

Programme Committee:

M. Baelmans, KUL, Belgium
A. Bar-Cohen, U. of Minnesota, USA
W. Claeys, U. Bordeaux, France
I. Barsony, KFKI-ATKI, Hungary
D. Blackburn, NIST Gaithersburg, USA
K. Azar, Advanced Thermal Solutions, USA
G. De Mey, Ghent U., Belgium
E. Suhir, Bell Laboratories, USA
E. Jones, US Air Force, USA
Y. Zorian, LogicVision, USA
A. Tay, Nat. U. Singapore, Singapore
U. Dillner, IPHT, Germany
J.M. Dorkel, LAAS, France
A. Rubio, UPC, Spain
B. Siegal, Thermal Eng. Ass., USA
J. Parry, Flomerics, United Kingdom
M. Kimura, U. Tohoku, Japan
J. Rantala, Nokia, Finland
Y. Joshi, U. of Maryland, USA
N. Sabry, Mentor Graphics, Cairo, Egypt
J.B. Saulnier, ENSMA, France
H. Pape, Infineon Technologies, Germany
A. Napieralski, TU Lodz, Poland
D. De Cogan, U. of East Anglia, United Kingdom
H. Jaouen, STMicroelectronics, France
J. Samitier, U. Barcelona, Spain
D. Copeland, Fujitsu Laboratories of America, USA
P. Tadayon, Intel, USA
K. Shenai, U. of Illinois, USA
M. Iyer, IME, Singapore
F. Christiaens, Alcatel Bell, Belgium
J. Janssen, Philips, The Netherlands
G. Digele, The Boston Cltg, Germany
E. Driessens, IMEC, Belgium
B. Guenin, AMKOR, USA
P. Raad, Southern Methodist U., USA
T. Tarter, Lightwave Microsystems, USA
O. Slattery, NMRC, Ireland
D. Agonafer, IBM Corp., USA
S. Ramminger, Siemens, Germany
P. Rodgers, Electronics Thermal Management, Ireland

The PROFIT session on Dynamic Measurements included the following presentations:

9.50	J. Altet ¹ , S. Dilhaire ² , J.-M. Rampnoux ² , A. Rubio ¹ , S. Grauby ² , S. Jorez ² , L.D. Patino Lopez ² , W. Claeys ² , S. Volt ³ 1U. Politècnica de Catalunya, Barcelona, Spain 2CPMOH/U. Bordeaux I, Talence, France 3Laboratory of Thermal Studies/ENSMA, Futuroscope, France	Four Different Approaches for the Measurement of the IC Surface Temperature: Application to Thermal Testing
10.10	V. Székely ¹ , M. Rencz ² , L. Pohl ² 1BUTE, Budapest, Hungary 2MicReD Ltd , Budapest, Hungary	Novelties in the Theory and Practice of Thermal Transient Measurements
10.30	H. Pape, D. Schweitzer Infineon Technologies AG, München, Germany	Thermal Impedance of Packages in Dual Cold Plate Environments
10.50	<i>Break</i>	
11.10	M. Rencz ¹ , V. Székely ² 1Micred Ltd, Budapest, Hungary 2BUTE, Budapest, Hungary	Determining Partial Thermal Resistances in a Heat-Flow Path with the Help of Transient Measurements
11.30	S. Orain ¹ , Y. Scudeller ¹ , T. Brousse ² 1Thermique-Energétique, Nantes, France 2Laboratoire de Génie des Matériaux, Nantes, France	Investigation of Structural Effects on Thin Film Thermal Conductivity
11.50	M.G. Burzo, P.L. Komarov, P.E. Raad Southern Methodist U., Dallas, USA	Influence of a Metallic Absorption Layer on the Quality of Thermal Conductivity Measurements by the Transient Thermo-Reflectance Method

The session has been moderated by C. Lasance.

The papers are included in the THERMINIC Workshop Proceedings, available separately.